

Search Notes

Application/Control No.

10/630,855

Examiner

Christopher M. Keehan

Applicant(s)/Patent under
Reexamination

ODELL ET AL.

Art Unit

1712

SEARCHED

Class	Subclass	Date	Examiner
428	447	6/13/2005	CMK
	450		
528	28		
525	474		
	422		
	431		
	432		
	435		
	436		
	445		
399	333		
	328		
	330		
	331		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
same as	above	6/13/2005	CMK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/13/2005	CMK
Inventor name search		

Search Notes (continued)

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SEARCHED

Class	Subclass	Date	Examiner
347	20		
	100		
	137		
430	124		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR